

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/710,298	CHEN ET AL.	
Examiner	Art Unit	
Don P. Le	2819	•

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SEARCHED						
Class	Subclass	Date	Examiner			
326	26, 27, 80, 81	4/20/2005	DL			
327	535-537	4/20/2005	DL			
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INI	INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner				
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S (INCLUDIN	SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR			
east		4/20/2005	DL			
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